

Notice of References Cited

Application/Control No.

10/555,474

Applicant(s)/Patent Under
Reexamination
MAIER ET AL.

Examiner

Jeffrey Lenihan

Art Unit

1796

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,822,840 A	04-1989	Kioka et al.	525/240
*	B	US-2006/0167185 A1	07-2006	Fuchs et al.	525/240
	C	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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	N	WO-0232985-A1	04-2002		Agarwal, P. K. et al	
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
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	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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